Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	327	(adjust\$3 with voltage) same (test\$3 with memory)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:36
L2	19	l1 and ((pullup or pull-up) with transistor\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:37
L3	10	365/201,200.ccls. and test\$3 and ((pullup or pull-up) with transistor\$1) and SRAM and ((modif\$4 or adjust\$3 or variable\$1) with bias)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:41
L6	53	365/201,200,230.06,226,190, 203-205,194,154,156.ccls. and (weak with test) and SRAM and transistor\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR .	ON	2005/09/29 15:44
L7	5	365/201,200,230.06,226,190, 203-205,194,154,156.ccls. and (weak with test) and SRAM and (transistor\$1 with (fuse\$1 or antifuse\$1))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR.	ON	2005/09/29 15:45
L8	51827	SRAM and memory .	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:45
L9	15872	18 and test\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:45
L10	25	I9 and ((weak adj write adj test adj mode) or WWTM)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:46

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L11	325	19 and bias near2 generat\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:47
L12	232	l11 and driver	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:47
L13	232	I12 and voltage	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:47
L14	226	I13 and transistor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:46
L15	113	114 and (pullup or pull-up)	US-PGPUP; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:4
L16	98	l15 and (pulldown or pull-down)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:49
L17	69	I16 and metal\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:49
L18	3	I9 and (metal-program\$4 or (metal adj program\$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:50

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L19	27	test\$3 and (metal-program\$4 or (metal adj program\$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DER:VENT; IBM_TDB	OR	ON	2005/09/29 15:51
L20	16 ·	I19 and memory	US-PGPUB; USPAT; USOCR; EPC; JPO; DER: VENT; IBM_TDB	OR	ON	2005/09/29 15:50
L21	9	I20 and (bias\$3 or voltage\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:51
L22	4	(bias adj2 generator) and (metal-program\$4 or (metal adj program\$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:53
L23	4966	circuit\$3 same (internal adj voltage)	US-FGPUB; USPAT; USCCR; EPC; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 16:04
L24	34	I1 and I23	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:54
L25	49	circuit\$3 same (internal adj voltage) same ((pullup or pull-up) with transistor\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 16:05
L26	. 16	circuit\$3 same (internal adj voltage) same ((pullup or pull-up) with transistor\$1) same ((pulldown or pull-down) with transistor\$1)	US-F GPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON .	2005/09/29 16:05